



PATENT
Attorney Docket No.: 16869P-017810US
Client Ref. No.: 210000889US2

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Takashi Hiroi et al.

Application No.: 09/802,693

Filed: March 8, 2001

For: A CIRCUIT PATTERN
INSPECTION METHOD AND
APPARATUS

Customer No.: 20350

Confirmation No.: 8024

Examiner: Brian P. Werner

Technology Center/Art Unit: 2621

**AMENDMENT UNDER 37 CFR 1.116
EXPEDITED PROCEDURE
EXAMINING GROUP 2621**

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Technology Center 2600

Mail Stop AF

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

In response to the Final Office Action mailed April 19, 2004 on the above-referenced application, please enter the following amendments and remarks:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 10 of this paper.